



CT3400A-R3

N-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DSS} 30 V
- Drain-Source On-Resistance
 - $R_{DS(ON)}$ 23.0mΩ, at V_{GS} = 10V, I_{DS} = 6.0A
 - $R_{DS(ON)}$ 26.0mΩ, at V_{GS} = 4.5V, I_{DS} = 5.0A
 - $R_{DS(ON)}$ 35mΩ, at V_{GS} = 2.5V, I_{DS} = 4.0A
- Continuous Drain Current at $T_A=25^\circ\text{C}$ I_D = 5.8A
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

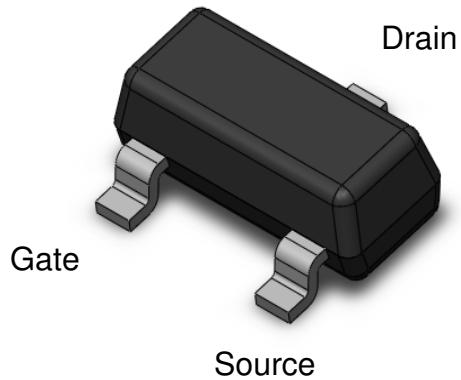
Applications

- Power Management
- LED Display
- DC-DC System
- LCD Panel

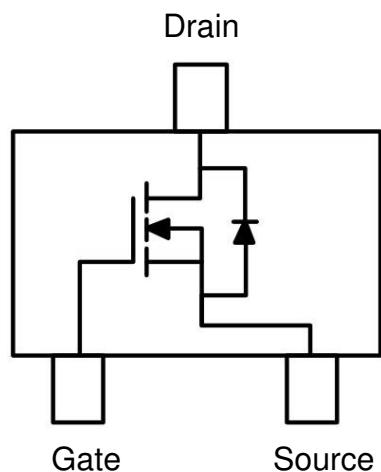
Description

The CT3400A-R3 uses high performance Trench Technology to provide excellent $R_{DS(ON)}$ and low gate charge which is suitable for most of the synchronous buck converter applications .

Package Outline



Schematic





CT3400A-R3

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Absolute Maximum Rating at 25°C

Symbol	Parameters	Ratings	Units	Notes
V_{DS}	Drain-Source Voltage	30	V	
V_{GS}	Gate-Source Voltage	± 12	V	
I_D	Continuous Drain Current @ $T_A=25^\circ\text{C}$	5.8	A	1
I_{DM}	Pulsed Drain Current	15	A	1
P_D	Total Power Dissipation @ $T_A=25^\circ\text{C}$	1.4	W	2
T_{STG}	Storage Temperature Range	-55 to 150	°C	
T_J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{\Theta JA}$	Thermal Resistance Junction-Ambient ($t=10\text{s}$)		-	175	-	°C /W	1,4



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Electrical Characteristics $T_A = 25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
B_{VDSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D= 250\mu\text{A}$	30	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}$	-	-	1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 12\text{V}, V_{DS} = 0\text{V}$	-	-	± 100	nA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(\text{ON})}$	Drain-Source On-Resistance	$V_{GS} = 10\text{V}, I_D = 6.0\text{A}$	-	23.0	28	$\text{m}\Omega$	3
		$V_{GS} = 4.5\text{V}, I_D = 5.0\text{A}$	-	26.0	35	$\text{m}\Omega$	
		$V_{GS} = 2.5\text{V}, I_D = 4.0\text{A}$	-	35.0	50	$\text{m}\Omega$	
$V_{GS(\text{TH})}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	0.7	-	1.4	V	3

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{ISS}	Input Capacitance	$V_{DS} = 10\text{V},$ $V_{GS} = 0\text{V},$ $f=1\text{MHz}$	-	595	-	pF	
C_{OSS}	Output Capacitance		-	60	-		
C_{RSS}	Reverse Transfer Capacitance		-	48	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(\text{ON})}$	Turn-On Delay Time	$V_{DS} = 10\text{V},$ $V_{GS} = 4.5\text{V},$ $R_G = 6\Omega,$ $I_D = 5.8\text{A}$	-	2.1	-	ns	
T_R	Rise Time		-	31.0	-		
$T_{D(\text{OFF})}$	Turn-Off Delay Time		-	16.5	-		
T_F	Fall Time		-	6.5	-		
Q_G	Total Gate Charge	$V_{DS} = 10\text{V},$ $V_{GS} = 4.5\text{V},$ $I_D = 5.8\text{A}$	-	69	-	nC	
Q_{GS}	Gate-Source Charge		-	1.4	-		
Q_{GD}	Gate-Drain (Miller) Charge		-	2.1	-		



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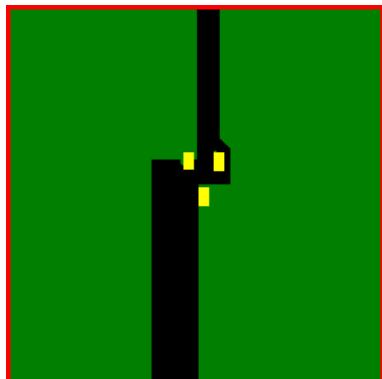
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Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_D = 1.0A$			1.2	V	
I_{SD}	Body Diode Continuous Current				1.0	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4
25.4 × 25.4 mm .
2 Oz Copper

Actual Size

3. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



Typical Characteristic Curves

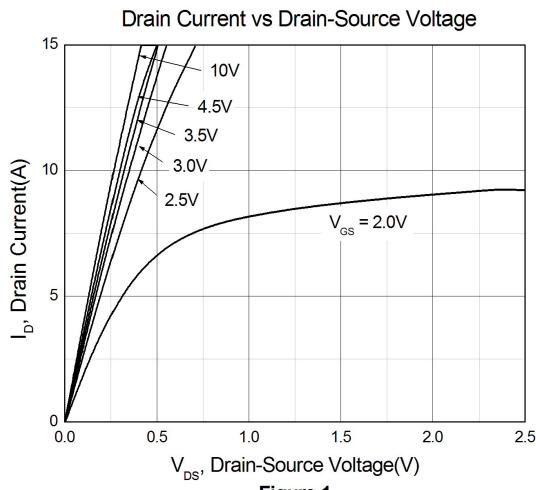


Figure 1

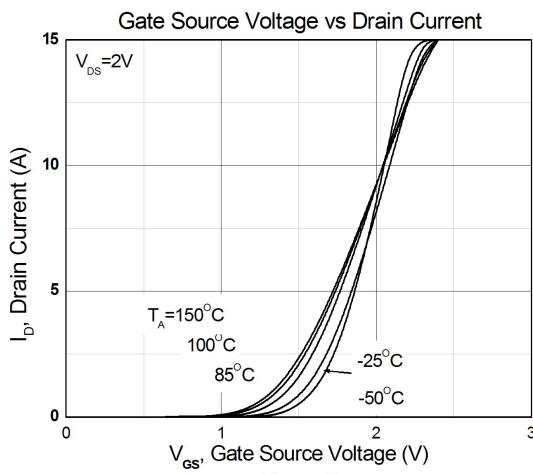


Figure 2

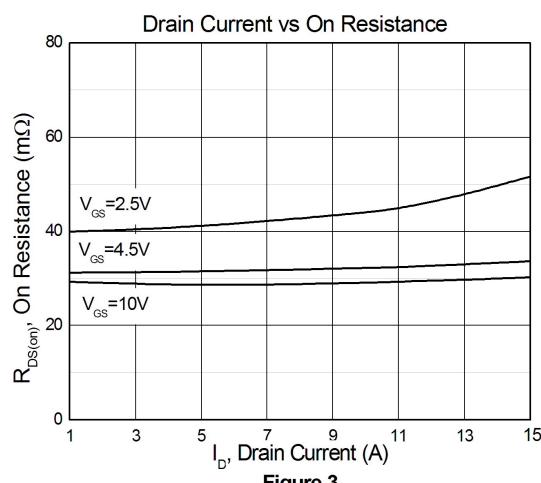


Figure 3

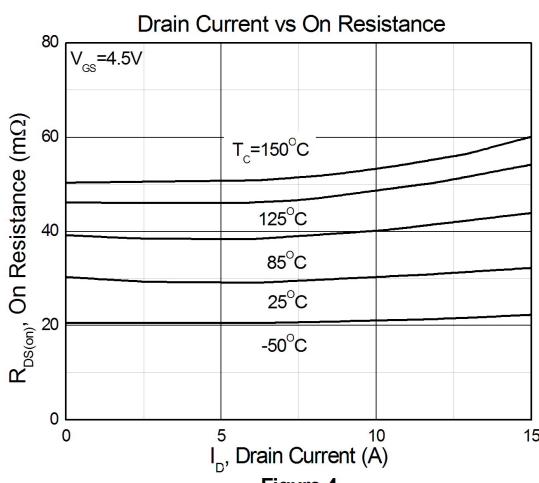


Figure 4

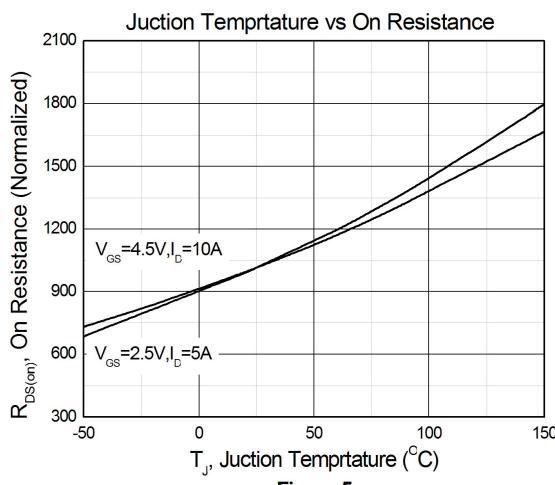


Figure 5

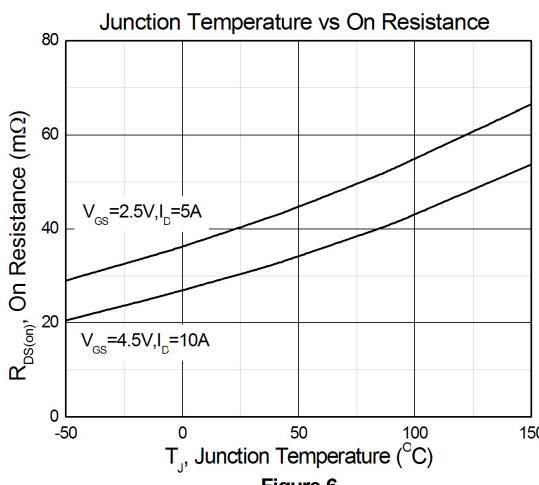
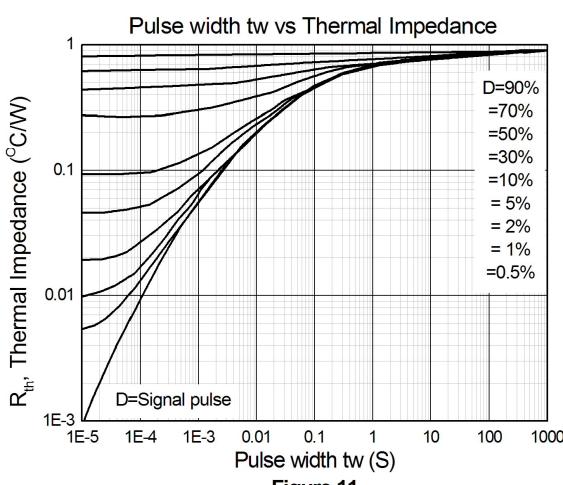
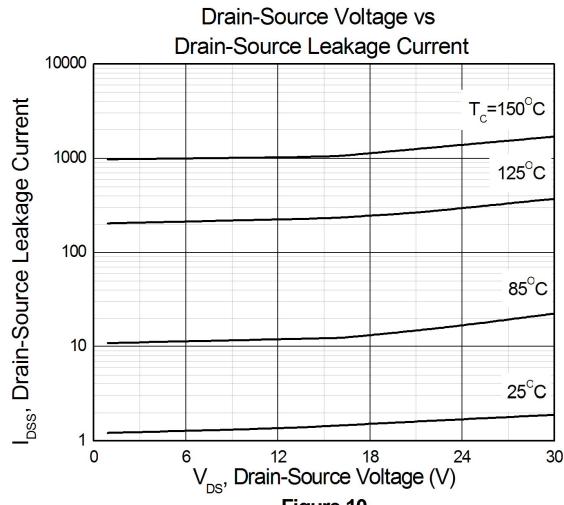
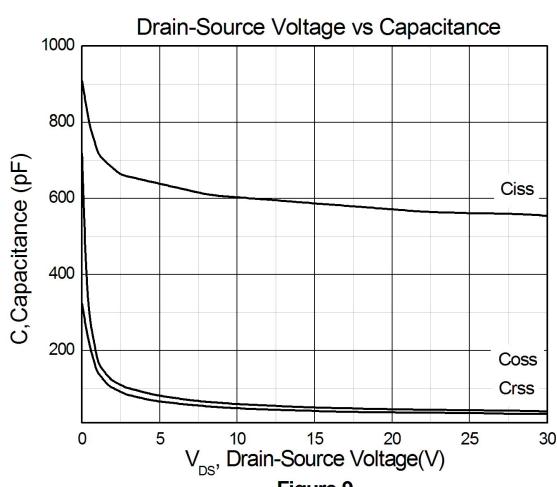
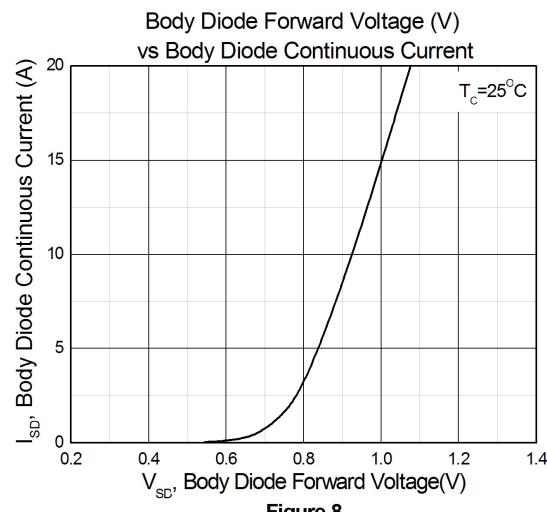
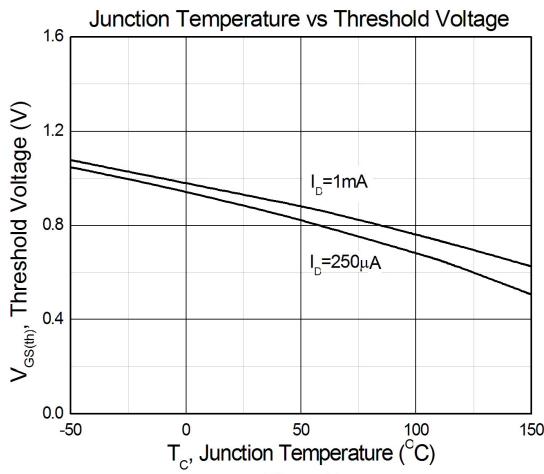


Figure 6



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Test Circuits & Waveforms

Figure 12: Gate Charge Test Circuit

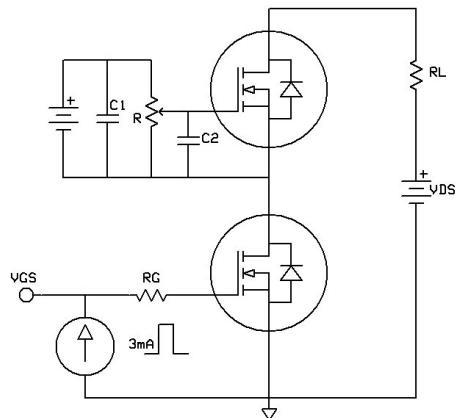


Figure 13: Gate Charge Waveform

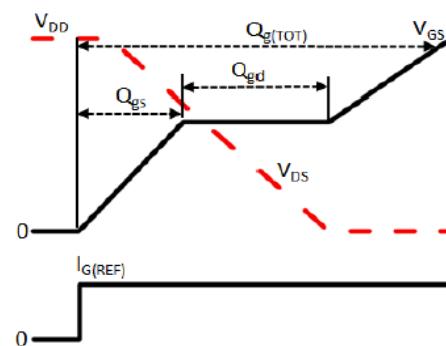


Figure 14: Switching Time Test Circuit

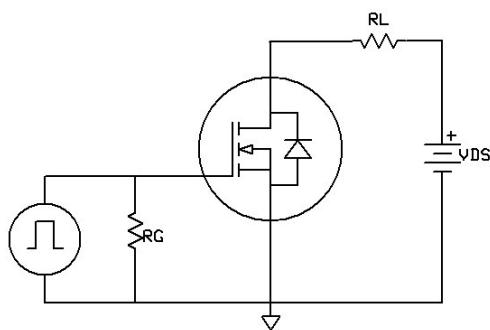
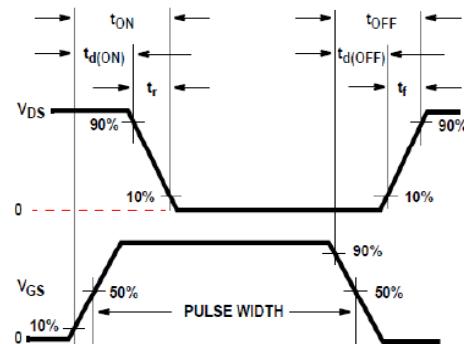


Figure 15: Switching Time Waveform

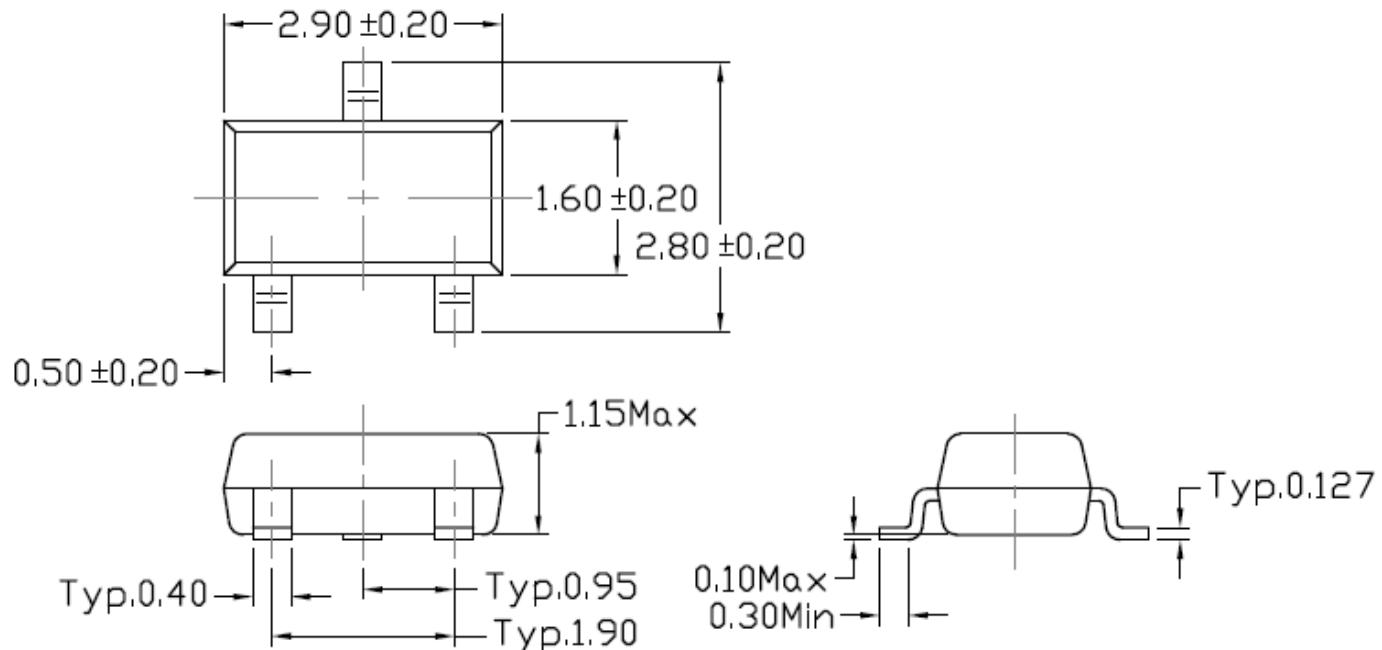




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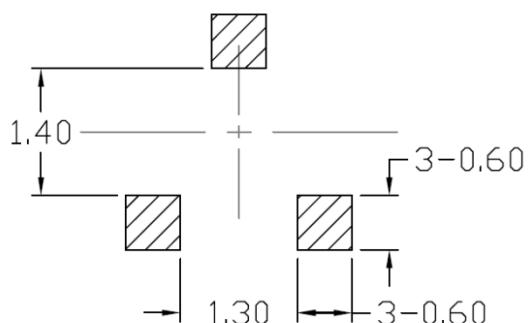
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Package Dimension (SC-59)



Note: Dimensions in mm

Recommended pad layout for surface mount leadform



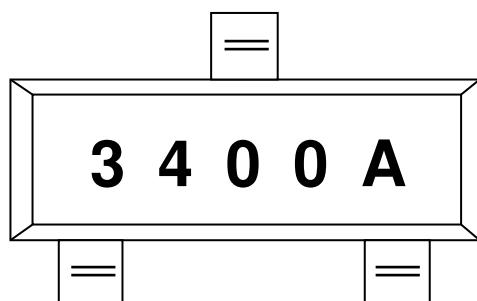
Note: Dimensions in mm



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Marking Information



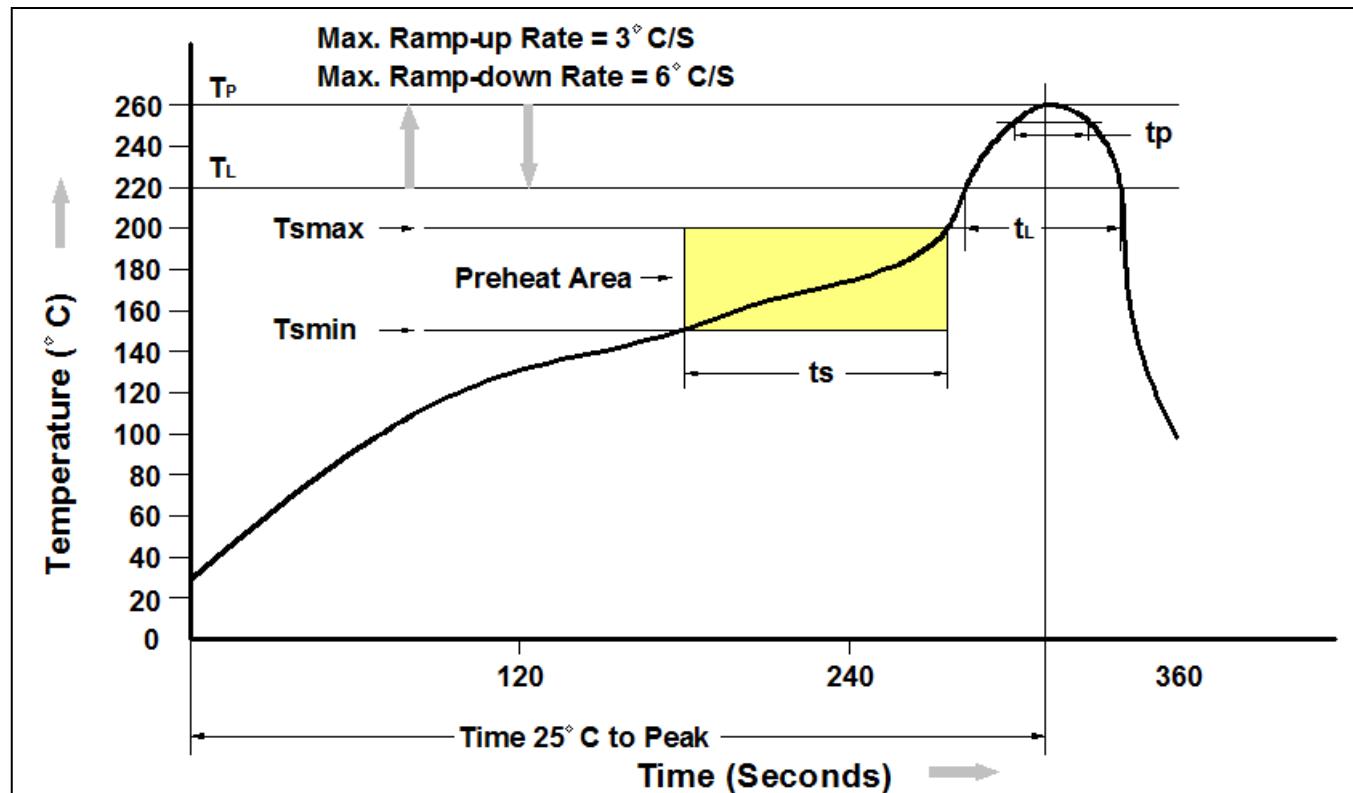
3400A : Device Number

Ordering Information

<i>Part Number</i>	<i>Description</i>	<i>Quantity</i>
CT3400A-R3	SC-59 Reel	3000 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T_{smin})	150 °C
Temperature Max. (T_{smax})	200 °C
Time (t_s) from (T_{smin} to T_{smax})	60-120 seconds
Ramp-up Rate (t_L to t_p)	3 °C/second max.
Liquidous Temperature (T_L)	217 °C
Time (t_L) Maintained Above (T_L)	60 – 150 seconds
Peak Body Package Temperature	260 °C +0 °C / -5 °C
Time (t_p) within 5°C of 260°C	30 seconds
Ramp-down Rate (T_p to T_L)	6 °C/second max
Time 25°C to Peak Temperature	8 minutes max.



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